D OR N PACKAGE (TOP VIEW)

1B

2B [2

3B

4B

5B 5

6B

7B [Ε

16 1 1C

15 2C

14 3C

13 AC

12 1 5C

11 1 6C

10 7C

9∏ сом

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- 500-mA Rated Collector Current (Single Output)
- High-Voltage Outputs . . . 50 V
- **Output Clamp Diodes**
- Inputs Compatible With Various Types of
- Interchangeable With ULN2001A Series

description

The ULQ2003A is a monolithic high-voltage, high-current Darlington transistor array. The device consists of seven non Darlington pairs that

feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of a single Darlington pair is 500 mA. The Darlington pairs may be paralleled for higher current capability. Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers. The ULQ2003A has a 2.7-k Ω series base resistor for each Darlington pair for operation directly with TTL or 5-V CMOS devices.

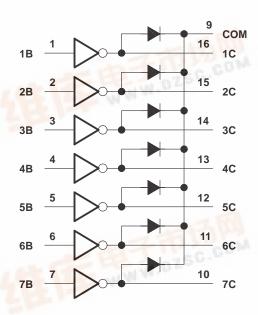
The ULQ2003A is offered in standard 16-pin dual in-line (N) and surface-mount (D) packaging. The device is characterized for operation over the junction temperature range of -40°C to 105°C.

logic symbol†

| | 2 | CLA | МР → | | СОМ |
|------------------------------|---------------------------------|-----|------|----------------------------------|--|
| 2B - 3B - 4B - 5B - | 1 2 3 4 5 6 7 | | | 16 15 14 13 12 11 | 1C 2C 3C 4C 5C 6C 7C |
| | | | | | , 0 |

†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

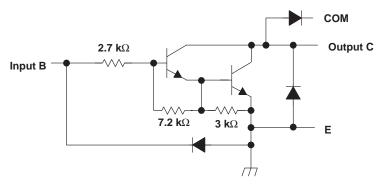
logic diagram (positive logic)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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schematics (each Darlington pair)



All resistor values shown are nominal.

absolute maximum ratings over operating temperature range (unless otherwise noted)†

| Collector-emitter voltage | 50 V |
|--|------------------------------|
| Clamp diode reverse voltage (see Note 1) | |
| Input voltage, V _I (see Note 1) | 30 V |
| Peak collector current (see Figures 13 and 14) | 500 mA |
| Output clamp current, I _{OK} | 500 mA |
| Total emitter-terminal current | –2.5 A |
| Continuous total power dissipation | See Dissipation Rating Table |
| Operating free-air temperature range, T _A | –40°C to 85°C |
| Operating junction temperature range, T _J | –40°C to 105°C |
| Storage temperature range, T _{Stq} | –65°C to 150°C |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds | 260°C |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.

DISSIPATION RATING TABLE

| PACKAGE | T _A = 25°C POWER RATING | DERATING FACTOR ABOVE T _A = 25°C | T _A = 85°C POWER RATING |
|---------|---------------------------------------|--|---------------------------------------|
| D | 950 mW | 7.6 mW/°C | 494 mW |
| N | 1150 mW | 9.2 mW/°C | 598 mW |



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electrical characteristics over operating junction temperature range, $T_J = -40^{\circ}C$ to $105^{\circ}C$

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|---------------------|--------------------------------------|--|-------------------------|-----|------|------|------|
| V _{I(on)} | On-state input voltage | V _{CE} = 2 V, See Figure 5 | $I_C = 200 \text{ mA}$ | | | 2.7 | V |
| | | | I _C = 250 mA | | | 2.9 | |
| | | | $I_C = 300 \text{ mA}$ | | | 3 | |
| VCE(sat) | Collector-emitter saturation voltage | I _I = 250 μA, See Figure 4 | $I_C = 100 \text{ mA},$ | | 0.9 | 1.2 | |
| | | I _I = 350 μA, See Figure 4 | $I_C = 200 \text{ mA},$ | | 1 | 1.4 | V |
| | | I _I = 500 μA, See Figure 4 | $I_C = 350 \text{ mA},$ | | 1.2 | 1.7 | |
| ICEX | Collector cutoff current | V _{CE} = 50 V, See Figure 1 | $I_{\parallel} = 0$, | | | 100 | μΑ |
| ٧ _F | Clamp forward voltage | $I_F = 350 \text{ mA},$ | See Figure 7 | | 1.7 | 2.2 | V |
| I _{I(off)} | Off-state input current | V _{CE} = 50 V, See Figure 2 | $I_C = 500 \mu A$, | 30 | 65 | | μΑ |
| lį | Input current | V _I = 3.85 V, | See Figure 3 | | 0.93 | 1.35 | mA |
| I _R | Clamp reverse current | $V_R = 50 V$, | See Figure 6 | | | 100 | μΑ |
| Ci | Input capacitance | $V_{I} = 0$, | f = 1 MHz | | 15 | 25 | pF |

switching characteristics over operating junction temperature, $T_J = -40^{\circ}C$ to $105^{\circ}C$

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-----------|--|---|---------------------|-----|-----|------|
| tPLH | Propagation delay time, low-to-high-level output | See Figure 8 | | 1 | 10 | μs |
| tPHL | Propagation delay time, high-to-low-level output | See Figure 6 | | 1 | 10 | μs |
| Vон | High-level output voltage after switching | $V_S = 50 \text{ V}, \qquad I_O \approx 300 \text{ mA},$ See Figure 9 | V _S -500 | | · | mV |

PARAMETER MEASUREMENT INFORMATION

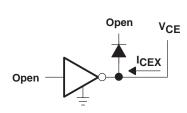


Figure 1. I_{CEX} Test Circuit

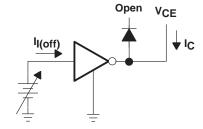


Figure 2. I_{I(off)} Test Circuit



PARAMETER MEASUREMENT INFORMATION

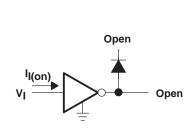


Figure 3. I_I Test Circuit

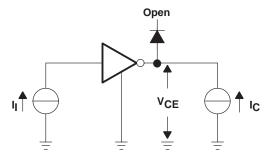


Figure 4. V_{CE(sat)} Test Circuit

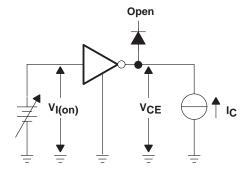


Figure 5. V_{I(on)} Test Circuit

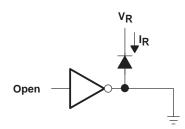


Figure 6. I_R Test Circuit

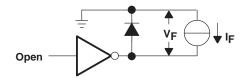


Figure 7. V_F Test Circuit

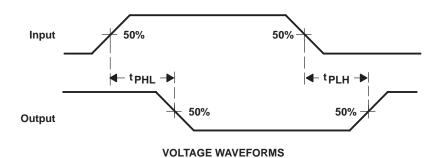
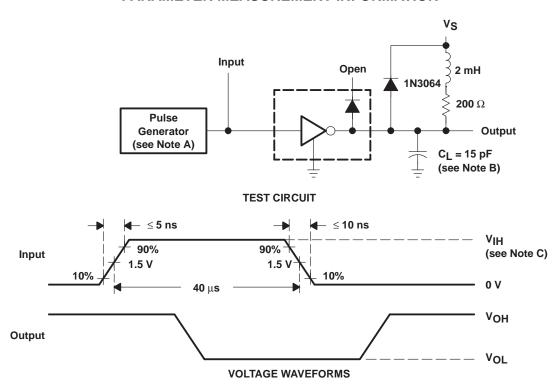


Figure 8. Propagation Delay Time Waveforms



PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: PRR = 12.5 kHz, Z_O = 50 Ω .

- B. C_L includes probe and jig capacitance.
- C. V_{IH} = 3 V

Figure 9. Latch-Up Test Circuit and Voltage Waveforms



TYPICAL CHARACTERISTICS

COLLECTOR-EMITTER SATURATION VOLTAGE COLLECTOR CURRENT (ONE DARLINGTON) 2.5 VCE(sat) - Collector-Emitter Saturation Voltage - V 2 $I_{I} = 250 \mu A$ $I_{I} = 350 \mu A$ $I_1 = 500 \mu A$ 1.5 1 0.5 0 100 200 300 400 500 600 700 800 IC - Collector Current - mA

COLLECTOR-EMITTER SATURATION VOLTAGE vs TOTAL COLLECTOR CURRENT

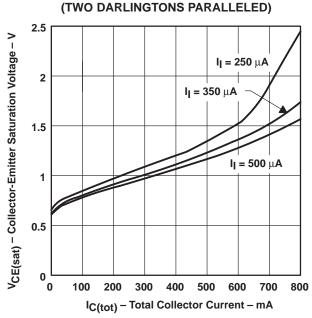


Figure 10

Figure 11

COLLECTOR CURRENT

INPUT CURRENT 500 $R_L = 10 \Omega$ 450 I_C - Collector Current - mA 400 V_S = 10 V 350 Vs = 8 V 300 250 200 150 100 50 0 25 100 125 150 175 50 200 I_I – Input Current – μ A

Figure 12

THERMAL INFORMATION

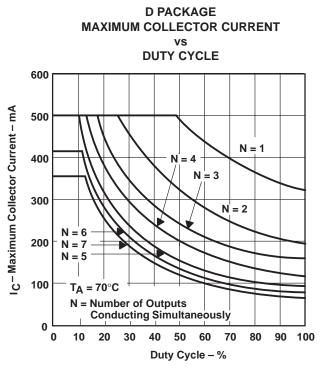
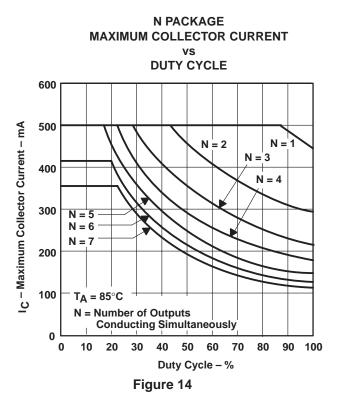


Figure 13



APPLICATION INFORMATION

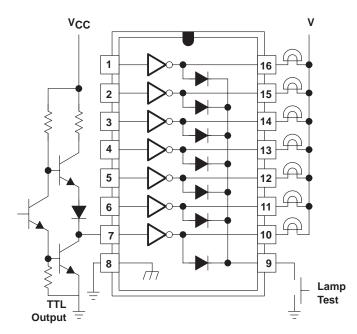


Figure 15. TTL to Load

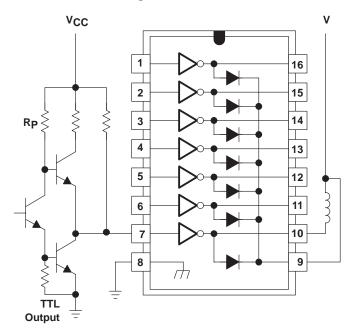


Figure 16. Use of Pullup Resistors to Increase Drive Current



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